Hierarchical architecture of spider attachment setae reconstructed from scanning nanofocus X-ray diffraction data

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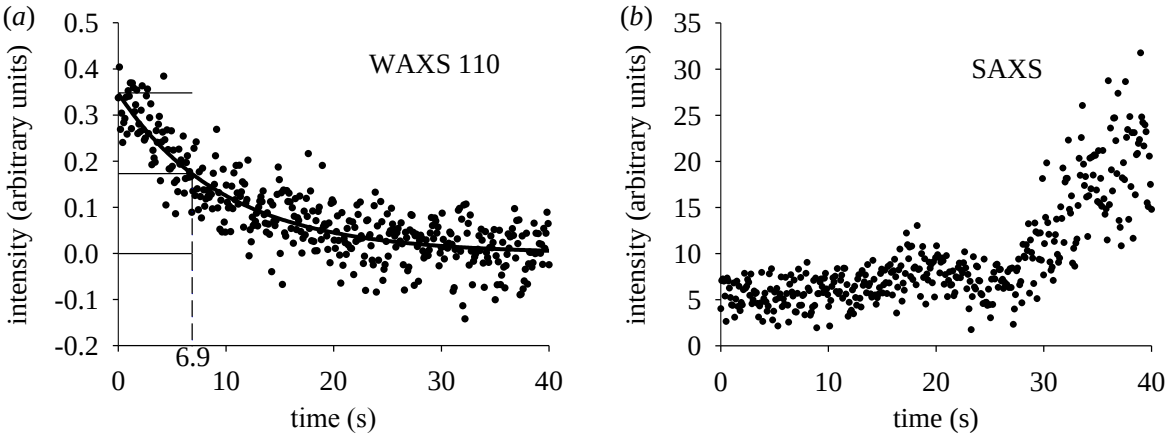

Figure S1. Modification of the X-ray diffraction signal intensity at 400-fold successive exposure by 0.1 s of an attachment hair to the focused X-ray beam at the ESRF. (*a*) Decrease of the equatorial 110 chitin wide-angle diffraction reflection. The exponential fit yields a half-life of signal intensity of 6.9 s exposure as indicated by the dashed line. The data points are shifted to the zero line of the asymptotic line fit. Negative intensity values are caused by subtraction of the background signal. (*b*) Increase of the SAXS signal intensity.